



## TGD N-Channel Enhancement Mode Power MOSFET

**Description**

The TGD01H29T uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of other applications.

**General Features**

- $V_{DSS} = 100V, I_D = 290A$
- $R_{DS(ON)} < 3.0m\Omega @ V_{GS}=10V$  (Typ:  $2.4m\Omega$ )

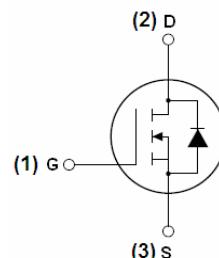
- Good stability and uniformity with high  $E_{AS}$
- High density cell design for ultra low  $R_{dson}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

**Application**

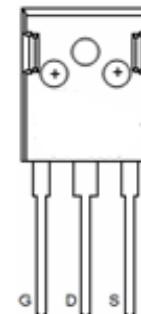
- DC motor drive
- High efficiency synchronous rectification in SMPS
- Uninterruptible power supply
- High speed power switching
- Hard switched and high frequency circuits

**100% UIS TESTED!**

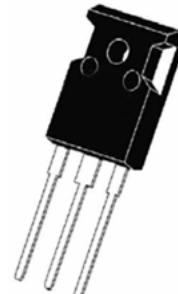
**100%  $\Delta V_{ds}$  TESTED!**



Schematic diagram



pin assignment



TO-247 top view

**Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
01H29T	01H29T	TO-247	-	-	-

**Absolute Maximum Ratings ( $T_c=25^\circ C$  unless otherwise noted)**

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DSS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	290	A
Drain Current-Continuous( $T_c=100^\circ C$ )	$I_D (100^\circ C)$	200	A
Pulsed Drain Current	$I_{DM}$	1120	A
Maximum Power Dissipation	$P_D$	460	W
Derating factor		3.07	W/ $^\circ C$



Single pulse avalanche energy <sup>(Note 3)</sup>	E <sub>AS</sub>	3500	mJ
Peak Diode Recovery dv/dt <sup>(Note 4)</sup>	dv/dt	10	V/ns
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 To 175	°C

**Thermal Characteristic**

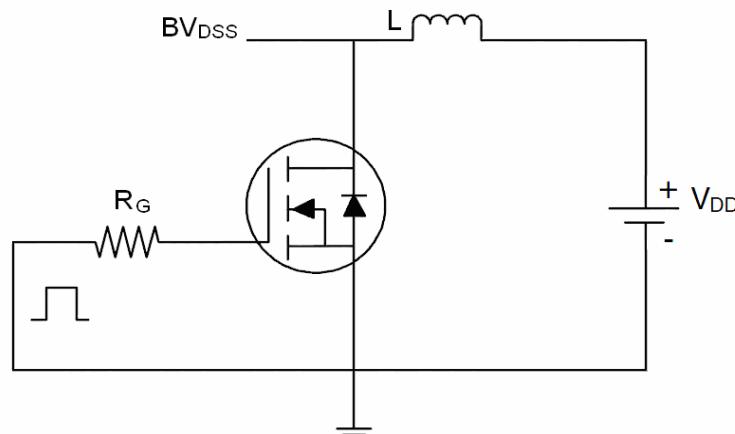
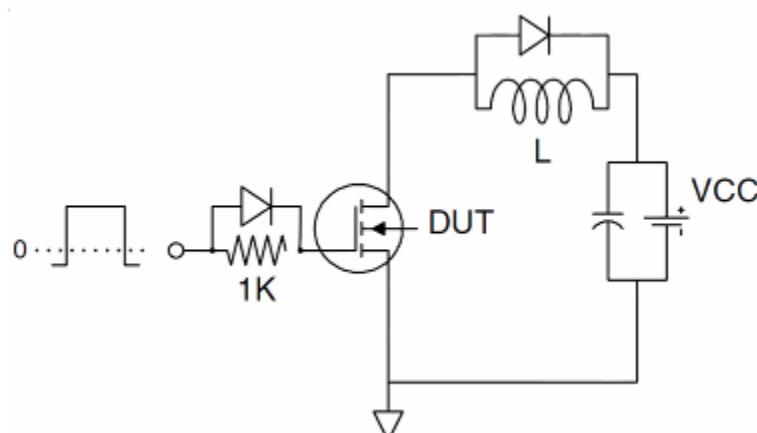
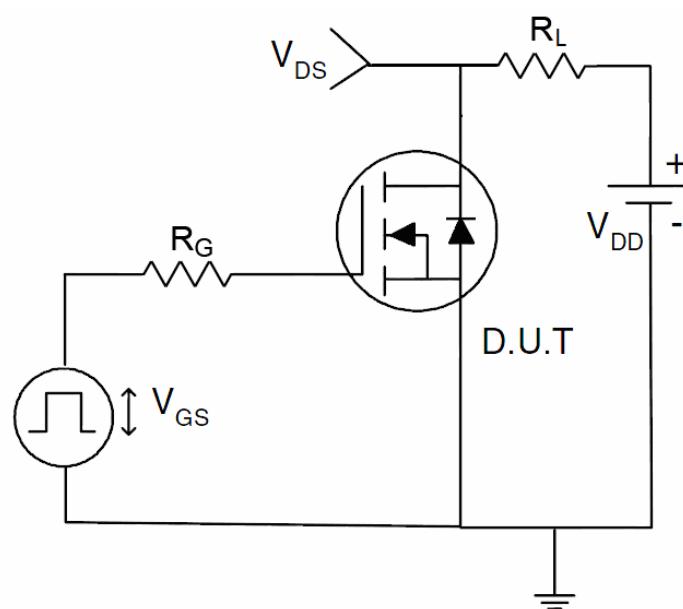
Thermal Resistance,Junction-to-Case <sup>(Note 1)</sup>	R <sub>θJC</sub>	0.33	°C/W
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**Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)**

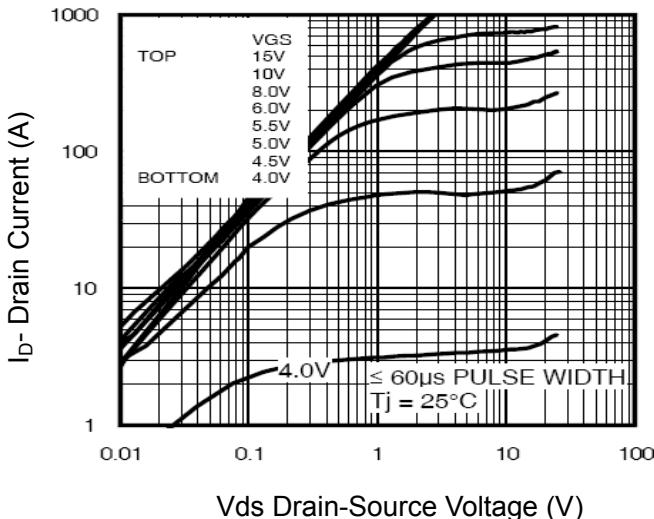
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	100	110	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±200	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2	3	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =40A	-	2.4	3.0	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =25V, I <sub>D</sub> =40A	310	-	-	S
<b>Dynamic Characteristics</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =50V, V <sub>GS</sub> =0V, F=1.0MHz	-	21000	-	PF
Output Capacitance	C <sub>oss</sub>		-	1652	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	1261	-	PF
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =50V, I <sub>D</sub> =40A V <sub>GS</sub> =10V, R <sub>GEN</sub> =1.2Ω (Note2)	-	44.6	-	nS
Turn-on Rise Time	t <sub>r</sub>		-	29.4	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>		-	139.8	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	36.4	-	nS
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =30V, I <sub>D</sub> =30A V <sub>GS</sub> =10V	-	586	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	123	-	nC
Gate-Drain Charge	Q <sub>gd</sub>		-	184	-	nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =40A	-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25°C, IF = 40A di/dt = 100A/μs <sup>(Note2)</sup>	-	88.9	-	nS
Reverse Recovery Charge	Q <sub>rr</sub>		-	139	-	nC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

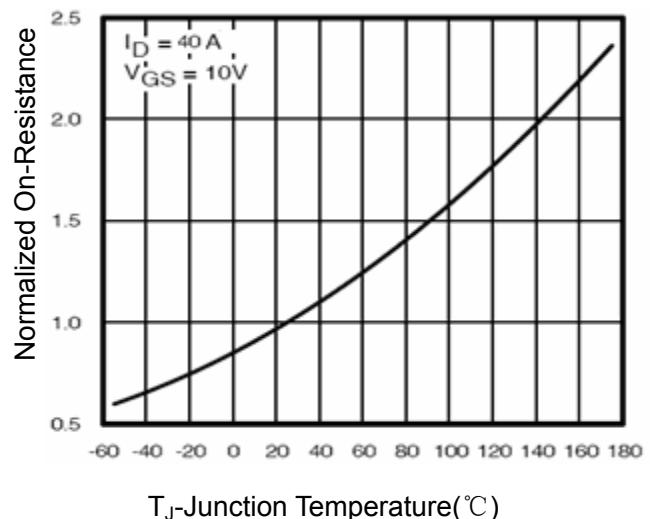
1. Surface Mounted on FR4 Board, t ≤ 10 sec.
2. Pulse Test: Pulse Width ≤ 400μs, Duty Cycle ≤ 2%.
3. EAS condition: T<sub>j</sub>=25°C, V<sub>DD</sub>=50V, V<sub>G</sub>=10V, L=0.5mH, R<sub>g</sub>=25Ω
4. I<sub>SD</sub>≤125A, di/dt≤260A/μs, V<sub>DD</sub>≤V<sub>(BR)DSS</sub>, T<sub>j</sub> ≤175°C

**Test circuit**
**1) E<sub>AS</sub> test Circuits**

**2) Gate charge test Circuit:**

**3) Switch Time Test Circuit:**


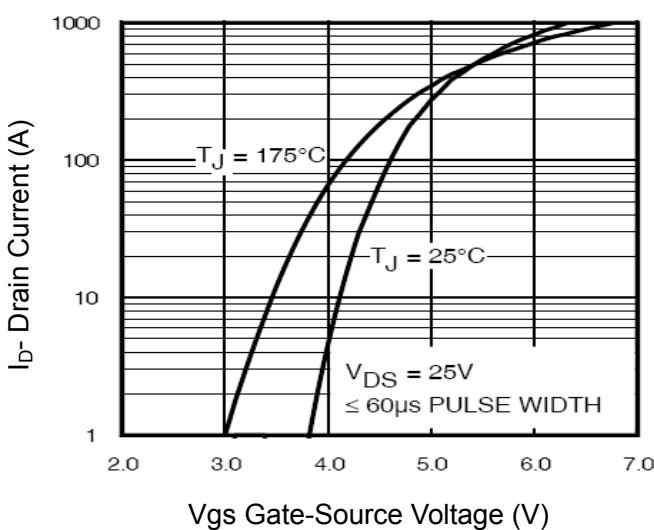
### Typical Electrical and Thermal Characteristics



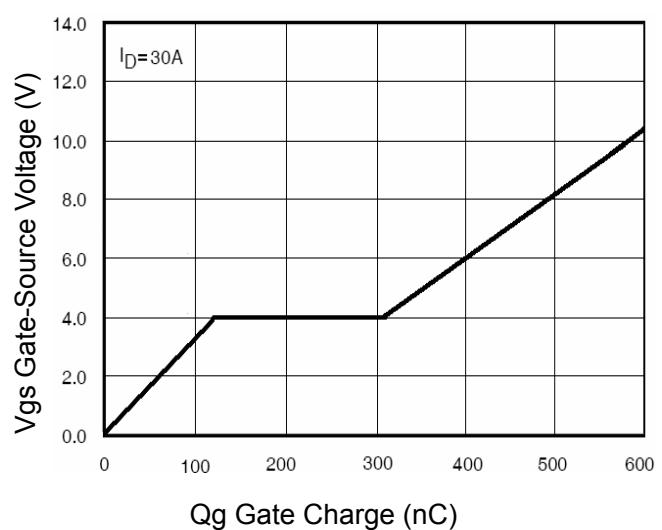
**Figure 1 Output Characteristics**



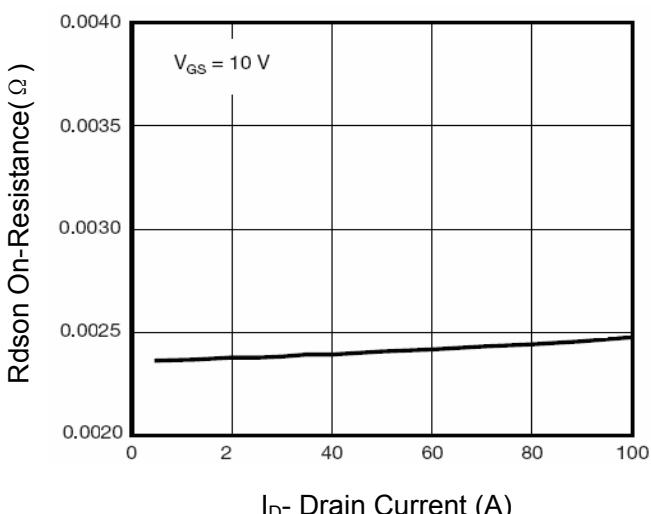
**Figure 4 Rdson-JunctionTemperature**



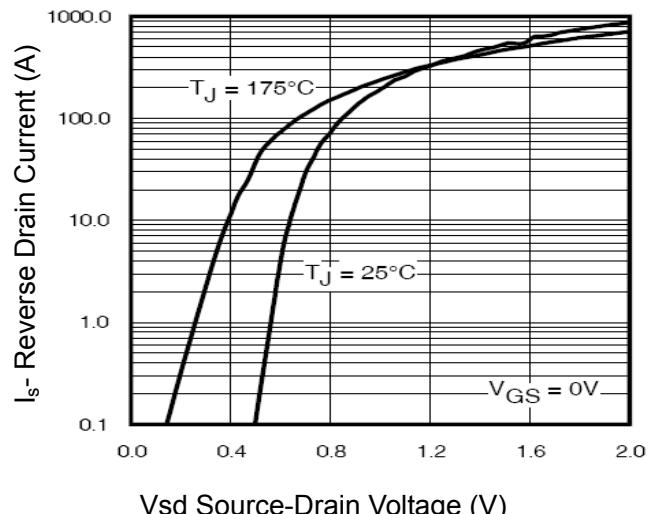
**Figure 2 Transfer Characteristics**



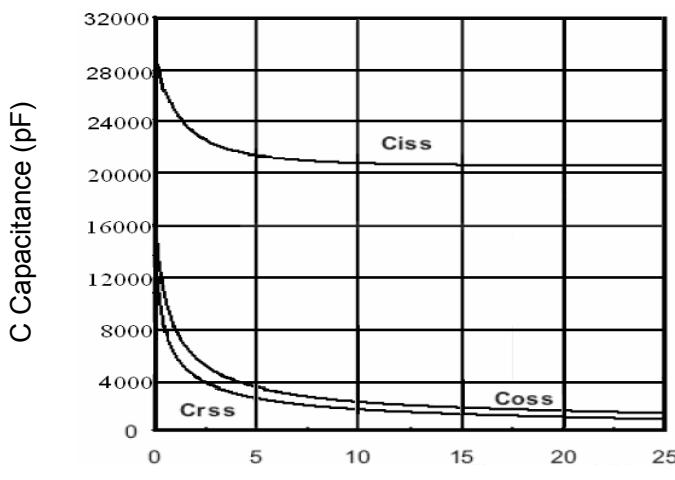
**Figure 5 Gate Charge**



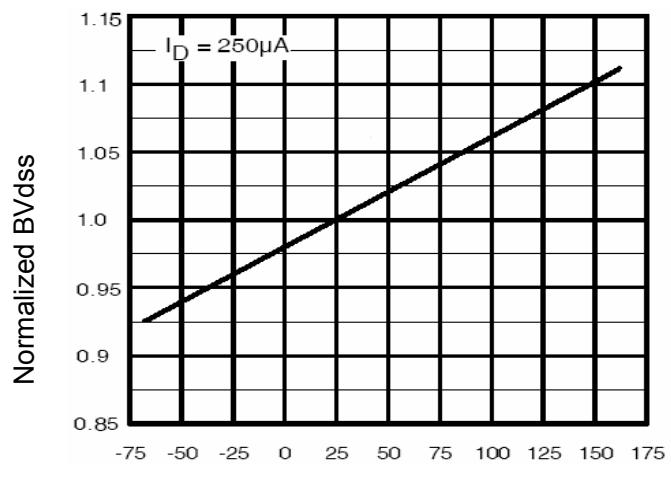
**Figure 3 Rdson- Drain Current**



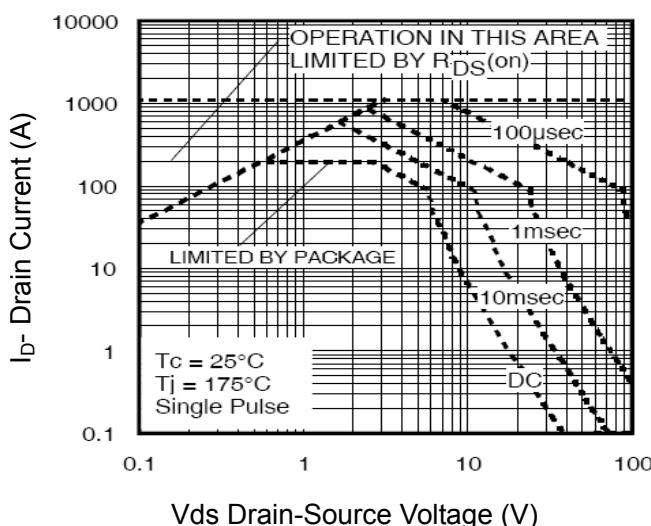
**Figure 6 Source- Drain Diode Forward**



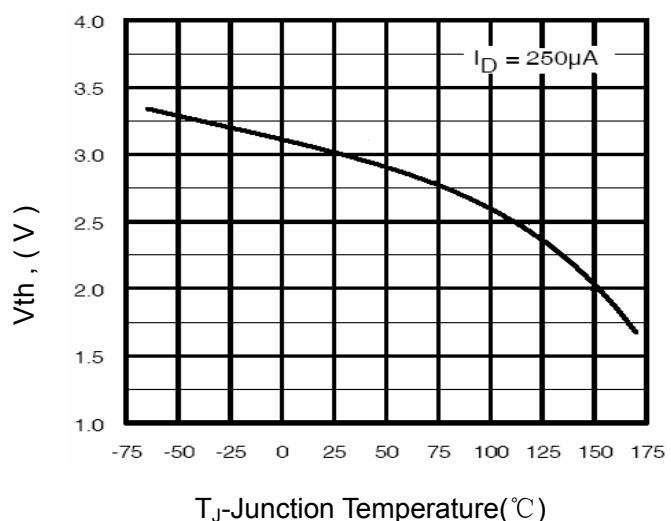
**Figure 7 Capacitance vs Vds**



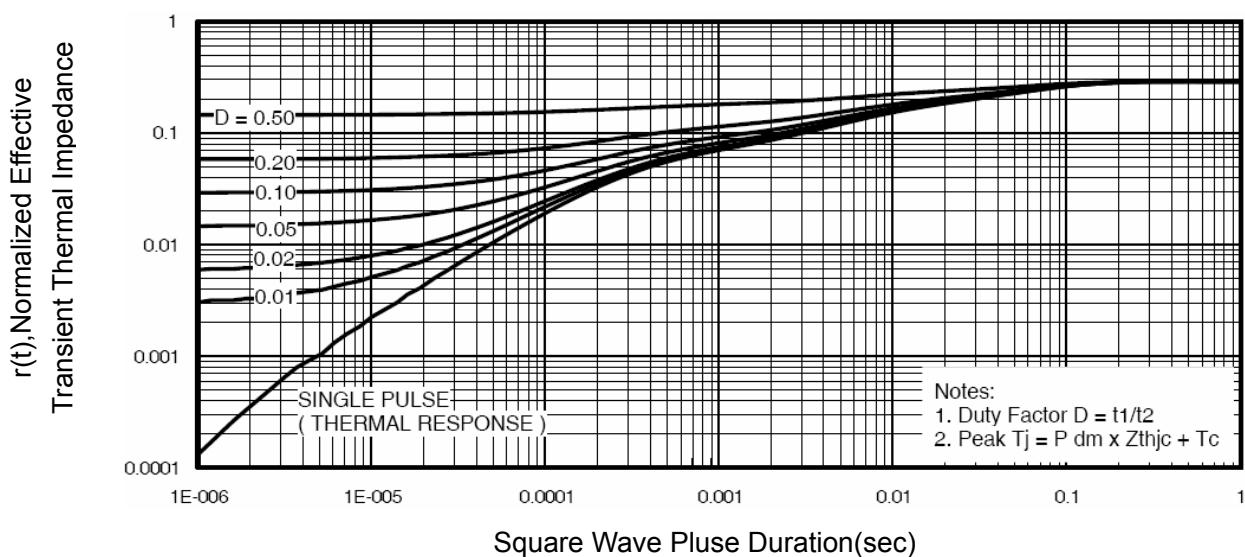
**Figure 9  $BV_{DSS}$  vs Junction Temperature**



**Figure 8 Safe Operation Area**

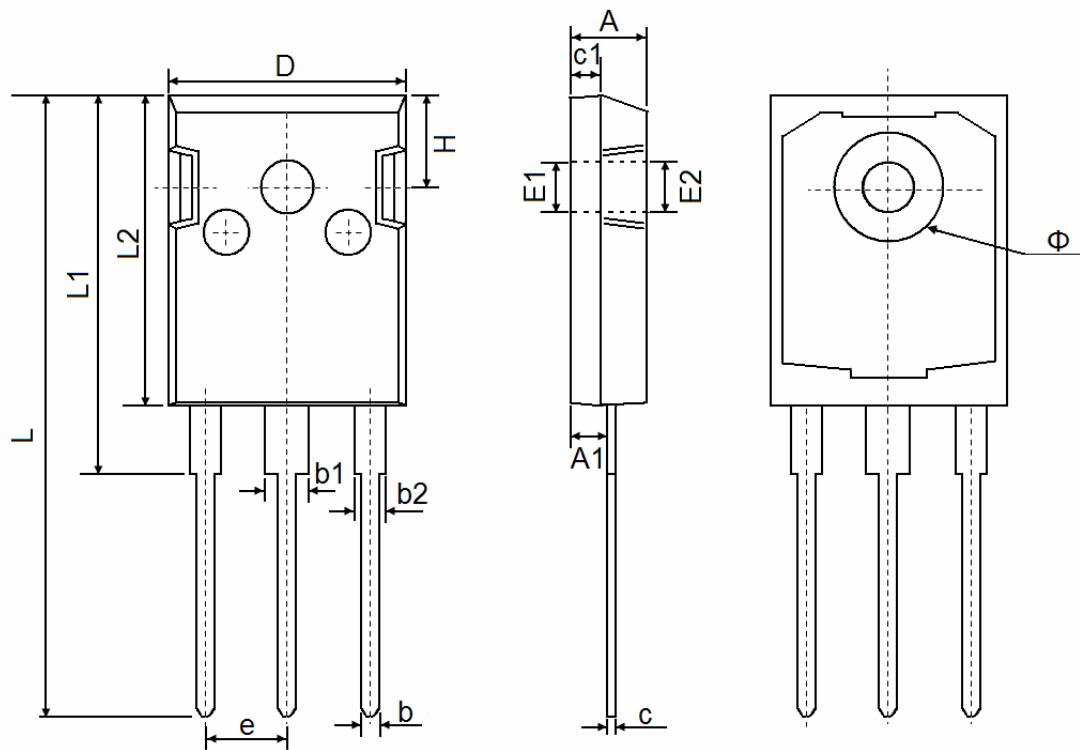


**Figure 10  $V_{GS(th)}$  vs Junction Temperature**



**Figure 11 Normalized Maximum Transient Thermal Impedance**

## TO-247 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.850	5.150	0.191	0.200
A1	2.200	2.600	0.087	0.102
b	1.000	1.400	0.039	0.055
b1	2.800	3.200	0.110	0.126
b2	1.800	2.200	0.071	0.087
c	0.500	0.700	0.020	0.028
c1	1.900	2.100	0.075	0.083
D	15.450	15.750	0.608	0.620
E1	3.500 REF		0.138 REF	
E2	3.600 REF		0.142 REF	
L	40.900	41.300	1.610	1.626
L1	24.800	25.100	0.976	0.988
L2	20.300	20.600	0.799	0.811
Φ	7.100	7.300	0.280	0.287
e	5.450 TYP		0.215 TYP	
H	5.980 REF		0.235 REF	